WHAT IS CLAIMED IS:

1. A semiconductor integrated circuit comprising:

a ROM for storing confidential data thereon;

a tester for testing the ROM; and

means for storing redundancy check data that has been obtained by performing a predetermined calculation on the confidential data,

wherein the tester includes a checker for performing the same type of calculation as the predetermined calculation on the confidential data that has been read out from the ROM, and

wherein a result of the calculation performed by the checker is compared to the redundancy check data stored on the storage means.

2. The integrated circuit of Claim 1, wherein the storage means is included in the ROM.

3. The integrated circuit of Claim 2, wherein the redundancy check data and the confidential data are stored at mutually different addresses on the ROM.

4. The integrated circuit of Claim 2, wherein the redundancy check data and the confidential data are stored at the same address on the ROM.

5. A method of testing a semiconductor integrated circuit including a ROM that stores confidential data thereon, the method comprising the steps of:

a) storing redundancy check data, which has been obtained by performing a predetermined calculation on the confidential data, on redundancy check data storage means of the integrated circuit;

b) reading out the confidential data from the ROM and performing the same type of calculation as the predetermined calculation on the confidential data read out; and

c) reading out the redundancy check data from the storage means and then comparing a result of the calculation performed in the step b) to the redundancy check data read out.